

Spring-loaded test probe

GKS-075 360 090 A 2000

Item GKS-075-0449



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Partner for Future Technology

- Well-established test probes for contacting PCBs
- For optimal contact to the test points (e.g. pads, vias, and pins), various tip styles with various diameters and finishes are available.
- Various spring forces available as well as versions with stainless steel springs suitable for high temperatures

General data

Product group	ICT / FCT (in-circuit test and function test)
Sub-product group	Bead probe
Series	GKS-075
Grid	1.91 mm [75 mil]
Contacting from	Pin, Post, Bead Probe
Magnetic	Yes
Installation type	Plug-in
Quick-exchange system	Yes
Adjustable installation height	No
Non-rotating	No
Compatible receptacle(s)	KS-075
Min. temperature	- 40 °C [- 104 °F]
Max. temperature	+ 80 °C [+ 176 °F]
RoHS-compliant	RoHS-3;6c

Electrical data

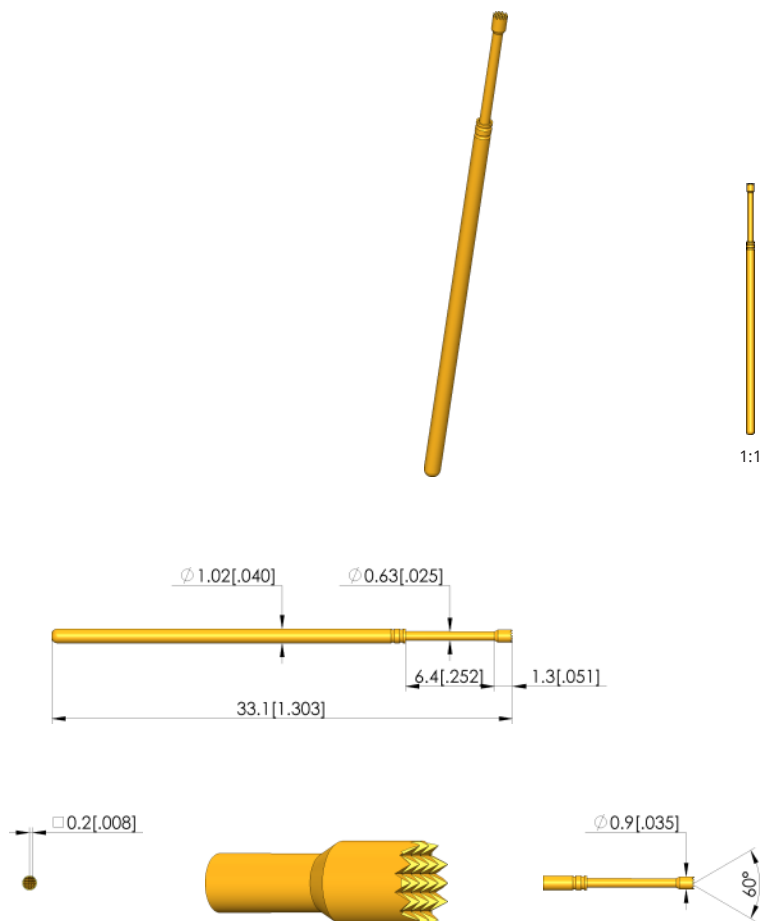
Current load capacity / rated current	4 A
Typical resistance (Ri)	<20 mOhm

Mechanical data

Total length	33.1 mm [1.30 in]
Barrel diameter	1.02 mm [.040 in]
Maximum stroke	6.35 mm [.25 in]
Spring pre-load	0.77 N [2.76 ozf]
Collar height	00
Spring force at working stroke	2 N [7.19 ozf]
Recommended working stroke	4.3 mm [.169 in]

Tip style data

Tip style	60 serrated, small grid
Tip diameter	0.9 mm [.035 in]
Tip style surface	A gold
Tip style material	3 CuBe



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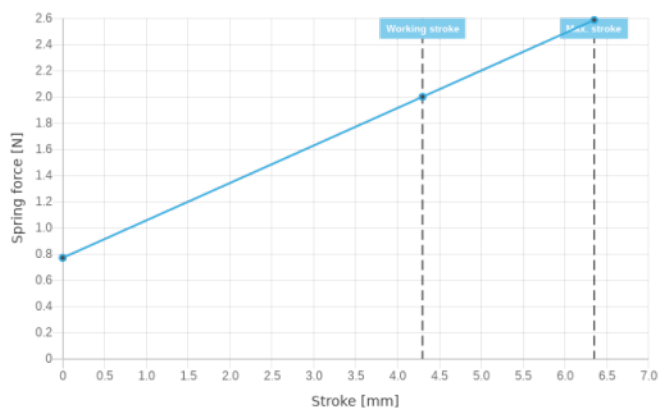
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Prices and delivery times on request.
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Learn more about
ICT/FCT Test probes

